

## CLAIMS

*What Is Claimed Is:*

1. A memory, comprising:

a memory column including,

5 a plurality of word lines,

a pair of data lines, wherein the plurality of word  
lines intersects the pair of data lines at  
intersections, and

memory cells, wherein each memory cell is configured

10 to be accessed by word lines and data lines of  
an intersection, wherein two distinct word  
lines of the plurality of word lines may both  
be active at a same time.

15 2. The memory of Claim 1, wherein the plurality of word  
lines includes a first pair of word lines and a second  
pair of word lines, wherein the first pair of word lines  
intersect the pair of data lines at a first intersection,  
wherein the second pair of word lines intersect the pair  
20 of data lines at a second intersection, wherein the  
memory cells include a first memory cell at the first  
intersection and a second memory cell at the second  
intersection.

25 3. The memory of Claim 2, wherein the first pair of word  
lines includes a first write word line and a first read

word line, wherein the second pair of word lines includes a second write word line and a second read word line.

4. The memory of Claim 3, wherein the two distinct word  
5 lines include the first write word line and the second read word line.

5. The memory of Claim 3, wherein the two distinct word  
10 lines include the first write word line and the first read word line.

6. The memory of Claim 1, further comprising a latch  
connected to a write word line, wherein the latch is  
configured to hold a decoded write word line activation  
15 signal of the write word line while a subsequent read word line activation signal of a read word line is being decoded.

7. The memory of Claim 1, wherein the pair of data lines  
20 includes a read data line and a write data line, wherein the memory further comprises:

a latch having a latch input and a latch output, wherein  
the latch input is connected to the read data line  
and to an input data line, wherein the latch is  
25 configured to hold data of the input data line or data of a connected memory cell, wherein the latch output is connected to the write data line.

8. The memory of Claim 7, wherein the memory column further comprises a sense amplifier configured to connect the read data line to the latch, wherein the read data line is connected to a sense amplifier input, wherein a sense amplifier output is connected to the latch input.
9. The memory of Claim 8, wherein when a same memory cell receives a consecutive read access, the memory is configured to read data held in a connected latch of the same memory cell and not data stored in the same memory cell.
10. The memory of Claim 1, wherein at least one of the memory cells is one of:  
a three-transistor dynamic memory cell; or  
a three-transistor dynamic memory cell including a write transistor, wherein the write transistor is a thin-channel polysilicon transistor having a channel region thickness of 5 nanometers or less.
11. The memory of Claim 8, wherein when a same memory cell receives a consecutive write access from an external input data bus and if the consecutive write access includes new data for a connected latch of the same memory cell, the connected latch and not the same memory

cell is configured to receive the consecutive write access.

12. The memory of Claim 8, further comprising:

5 a plurality of other memory columns, wherein the other memory columns are configured like the memory column;

a plurality of other sense amplifiers, wherein the other sense amplifiers are configured like the sense  
10 amplifier; and

a plurality of other latches, wherein the other latches are configured like the latch.

13. The memory of Claim 12, wherein when a same row of memory  
15 cells receives a consecutive read access, the memory is configured to read data held in latches and not data stored in the same row of memory cells.

14. The memory of Claim 12, wherein when a same row of memory  
20 cells receives a consecutive write access from an external input data bus and if the consecutive write access includes new data for a particular latch of the same row of memory cells, the particular latch and not a connected memory cell of the particular latch is  
25 configured to receive the consecutive write access.

15. The memory of Claim 8, further comprising another memory column configured like the memory column, wherein the memory column and the other memory column share the latch, wherein the memory is configured to conserve space on a silicon die in which the memory is fabricated due to sharing of the latch.

16. A memory, comprising:

a memory column including a pair of data lines having a

read data line and a write data line; and

a latch including a latch input and a latch output,

wherein the latch input is connected to the read

data line and to an input data line, wherein the

latch is configured to hold data of the input data

line, wherein the latch output is connected to the

write data line.

17. The memory of Claim 16, further comprising a sense amplifier configured to connect the read data line to the latch, wherein the read data line is connected to a sense amplifier input, wherein a sense amplifier output is connected to the latch input.

18. The memory of Claim 17, wherein the memory column further includes:

a plurality of word lines, wherein the plurality of word lines intersects the pair of data lines at intersections;

memory cells, wherein each memory cell is configured to be accessed by word lines and data lines of an intersection, wherein two distinct word lines of the plurality of word lines may both be active at a same time.

10 19. The memory of Claim 18, wherein when a same memory cell receives a consecutive read access, the memory is configured to read data held in a connected latch of the same memory cell and not data stored in the same memory cell.

15 20. The memory of Claim 17, wherein when a same memory cell receives a consecutive write access from an external input data bus and if the consecutive write access includes new data for a connected latch of the same memory cell, the connected latch and not the same memory cell is configured to receive the consecutive write access.